INFORMATION DISCLOSURE CITATION

Docket Number (Optional)	Application Number		
FIS9-2001-0254US1	10/035,061		
Applicant(s)			
AUSSCHNITT ET AL.			
Filing Date	Group Art Unit		

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			Filing Date 12/28/20	Filing Date 12/28/2001		Group Art Unit 2877			
			U.S. 1	PATENT DOCUMENTS					
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			U.S. PATENT	APPLICATION PUBLICATIONS					
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS FILING DATE IF APPROPRIATE			
			FOREIC	ON PATENT DOCUMENTS				<u> </u>	
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO		
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				gs for determination of equival . 70 - 76, Date of Publication 19 tions on the performance of the					
		SPIE 4000 - "Impact of high order aberrations on the performance of the aberration monitor" - Dirksen et al Proceedings SPIE, Vol. 4000, pp. 9 - 17, Date of Publication 2000, USA SPIE 4000 - "In-situ measurement of lens aberrations" - Farrar et al Proceedings SPIE, Vol. 4000, pp. 18 - 29, Date of Publication 2000, USA							
°		Publication 2000, USA							
EXAMINE	CR .		- -	DATE CONSIDERED					

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